

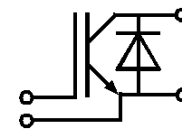
Absolute Maximum Ratings		Values		Units
Symbol	Conditions <sup>1)</sup>			
V <sub>CES</sub>		1700		V
V <sub>CGR</sub>	R <sub>GE</sub> = 20 kΩ	1700		V
I <sub>C</sub>	T <sub>case</sub> = 25/80 °C	440 / 300		A
I <sub>CM</sub>	T <sub>case</sub> = 25/80 °C; t <sub>p</sub> = 1 ms	880 / 600		A
V <sub>GES</sub>		± 20		V
P <sub>tot</sub>	per IGBT, T <sub>case</sub> = 25 °C	2500		W
T <sub>j</sub> , (T <sub>stg</sub> )		- 40 ... +150 (125)		°C
V <sub>isol</sub>	AC, 1 min.	4000		V
humidity	DIN 40 040	Class F		
climate	DIN IEC 68 T.1	40/125/56		
Inverse Diode <sup>8)</sup>			D1 S	
I <sub>F</sub> = - I <sub>C</sub>	T <sub>case</sub> = 25/80 °C	300 / 200	400 / 270	A
I <sub>FM</sub> = - I <sub>CM</sub>	T <sub>case</sub> = 25/80 °C; t <sub>p</sub> = 1 ms	880 / 600	880 / 600	A
I <sub>FSM</sub>	t <sub>p</sub> = 10 ms; sin.; T <sub>j</sub> = 150 °C	2900	4400	A
I <sub>t</sub> <sup>2</sup>	t <sub>p</sub> = 10 ms; T <sub>j</sub> = 150 °C	42000	96000	A <sup>2</sup> s

## SEMITRANS® M IGBT Modules

**SKM 400 GA 173 D  
SKM 400 GA 173 D1 S**



SEMITRANS 4



GA

### Features

- MOS input (voltage controlled)
- N channel, Homogeneous Si
- Low inductance case
- Very low tail current with low temperature dependence
- High short circuit capability, self limiting to 6 \* I<sub>Cnom</sub>
- Latch-up free
- Fast & soft inverse CAL diodes<sup>8)</sup>
- Isolated copper baseplate using DCB Direct Copper Bonding
- Large clearance (13 mm) and creepage distances (20 mm).

### Typical Applications:

- AC inverter drives on mains 575 - 750 V<sub>AC</sub>
- DC bus voltage 750 - 1200 V<sub>DC</sub>
- Public transport
- Switching (not for linear use)

Characteristics		min.	typ.	max.	Units
Symbol	Conditions <sup>1)</sup>				
V <sub>(BR)CES</sub>	V <sub>GE</sub> = 0, I <sub>C</sub> = 5,6 mA	≥ V <sub>CES</sub>	-	-	V
V <sub>GE(th)</sub>	V <sub>GE</sub> = V <sub>CE</sub> , I <sub>C</sub> = 20 mA	4,8	5,5	6,2	V
I <sub>CES</sub>	V <sub>GE</sub> = 0 } T <sub>j</sub> = 25 °C	-	-	2	mA
	V <sub>CE</sub> = V <sub>CES</sub> } T <sub>j</sub> = 125 °C	-	-	4,5	mA
I <sub>GES</sub>	V <sub>GE</sub> = 20 V, V <sub>CE</sub> = 0 V	-	-	400	nA
V <sub>CEsat</sub>	I <sub>C</sub> = 300 A } V <sub>GE</sub> = 15 V;	-	3,0(4,3)	3,9(5)	V
V <sub>CEsat</sub>	I <sub>C</sub> = 400 A } T <sub>j</sub> = 25 (125) °C	-	3,8(5,5)	-	V
g <sub>fs</sub>	V <sub>CE</sub> = 20 V, I <sub>C</sub> = 300 A	108	-	-	S
C <sub>CHC</sub>	per IGBT	-	-	400	pF
C <sub>ies</sub>	V <sub>GE</sub> = 0	-	44	-	nF
C <sub>oes</sub>	V <sub>CE</sub> = 25 V	-	3,5	-	nF
C <sub>res</sub>	f = 1 MHz	-	1	-	nF
L <sub>CE</sub>		-	-	20	nH
t <sub>d(on)</sub>	V <sub>CC</sub> = 1200 V	-	550	-	ns
t <sub>r</sub>	V <sub>GE</sub> = + 15 V / - 15 V <sup>3)</sup>	-	120	-	ns
t <sub>d(off)</sub>	I <sub>C</sub> = 300 A, ind. load	-	850	-	ns
t <sub>f</sub>	R <sub>Gon</sub> = R <sub>Goff</sub> = 2 Ω	-	50	-	ns
E <sub>on</sub>	T <sub>j</sub> = 125 °C	-	180	-	mWs
E <sub>off</sub>		-	10	-	mWs
Inverse Diode <sup>8)</sup>					
V <sub>F</sub> = V <sub>EC</sub>	I <sub>F</sub> = 300 A } V <sub>GE</sub> = 0 V;	-	2,2(1,9)	2,7(2,4)	V
V <sub>F</sub> = V <sub>EC</sub>	I <sub>F</sub> = 400 A } T <sub>j</sub> = 25 (125) °C	-	2,46(2,25)	-	V
V <sub>TO</sub>	T <sub>j</sub> = 125 °C	-	1,3	1,5	V
r <sub>T</sub>	T <sub>j</sub> = 125 °C	-	2,9	3,2	mΩ
I <sub>RR</sub>	I <sub>F</sub> = 300 A; T <sub>j</sub> = 25 (125) °C <sup>2)</sup>	-	120(170)	-	A
Q <sub>rr</sub>	I <sub>F</sub> = 300 A; T <sub>j</sub> = 25 (125) °C <sup>2)</sup>	-	30(72)	-	μC
Diodes of "D1" <sup>8)</sup>					
V <sub>F</sub> = V <sub>EC</sub>	I <sub>F</sub> = 300 A } V <sub>GE</sub> = 0 V;	-	2,1(1,8)	2,4	V
V <sub>F</sub> = V <sub>EC</sub>	I <sub>F</sub> = 400 A } T <sub>j</sub> = 25 (125) °C	-	2,2(2,1)	2,7	V
V <sub>TO</sub>	T <sub>j</sub> = 125 °C	-	1,3	1,5	V
r <sub>T</sub>	T <sub>j</sub> = 125 °C	-	2	2,5	mΩ
I <sub>RR</sub>	I <sub>F</sub> = 300 A; T <sub>j</sub> = 25 (125) °C <sup>2)</sup>	-	120(180)	-	A
Q <sub>rr</sub>	I <sub>F</sub> = 300 A; T <sub>j</sub> = 25 (125) °C <sup>2)</sup>	-	60(85)	-	μC
Thermal Characteristics					
R <sub>thjc</sub>	per IGBT	-	-	0,05	°C/W
R <sub>thjc</sub>	per diode D / "D1 S"	-	-	0,17/0,12	°C/W
R <sub>thch</sub>	per module	-	-	0,038	°C/W

<sup>1)</sup> T<sub>case</sub> = 25 °C, unless otherwise specified

<sup>2)</sup> I<sub>F</sub> = - I<sub>C</sub>, V<sub>R</sub> = 1200 V, - di<sub>F</sub>/dt = 1500 A/μs, V<sub>GE</sub> = 0 V

<sup>3)</sup> Use V<sub>GEoff</sub> = -5 ... -15 V

<sup>8)</sup> CAL = Controlled Axial Lifetime Technology.

**Cases and mech. data → B6-276  
"D1S" → B6-212**

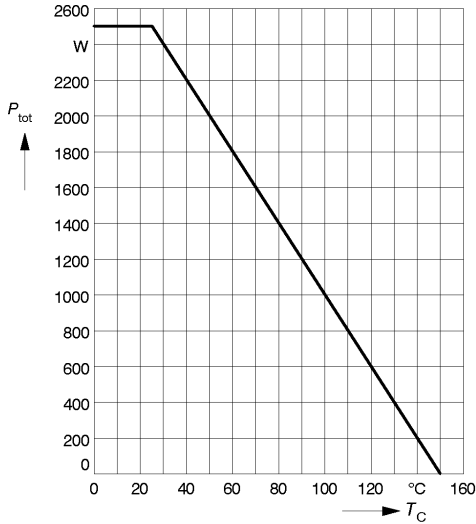


Fig. 1 Rated power dissipation  $P_{tot} = f(T_C)$

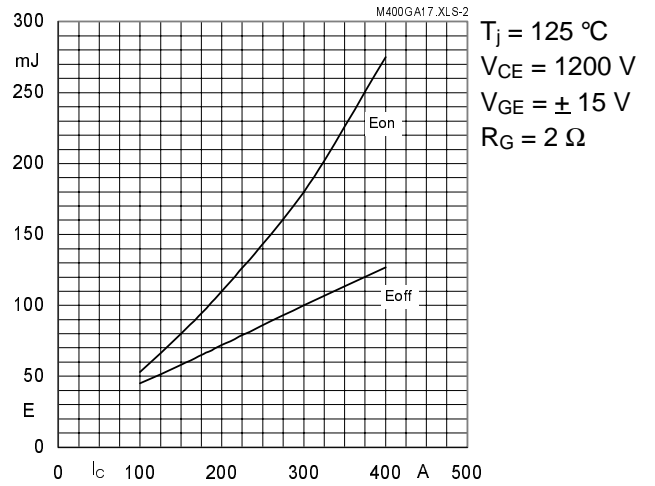


Fig. 2 Turn-on /off energy =  $f(I_C)$

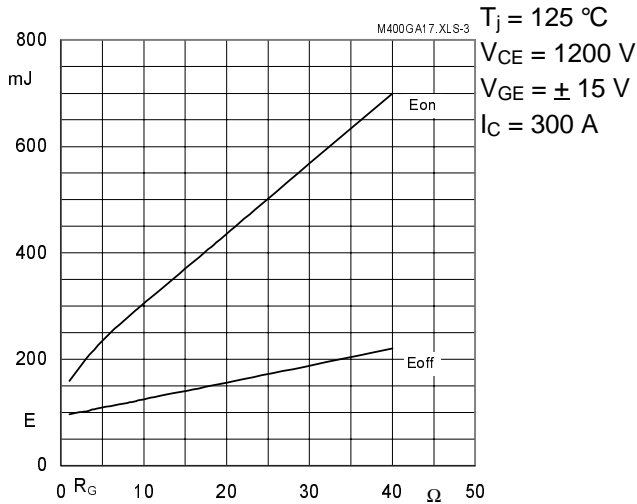


Fig. 3 Turn-on /off energy =  $f(R_G)$

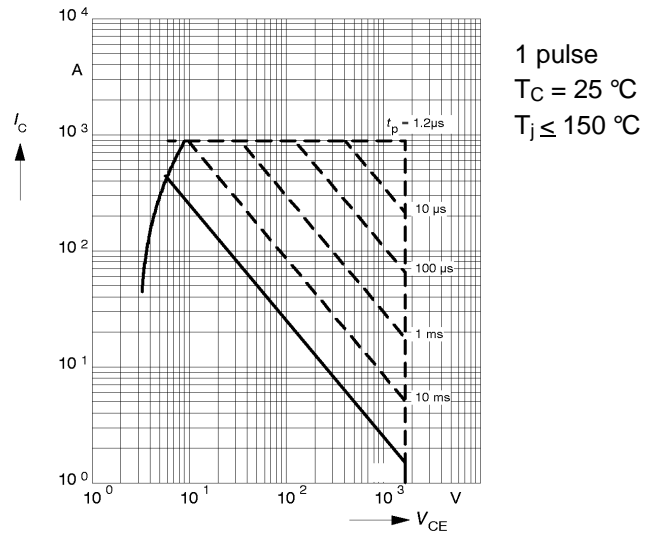


Fig. 4 Maximum safe operating area (SOA)  $I_C = f(V_{CE})$

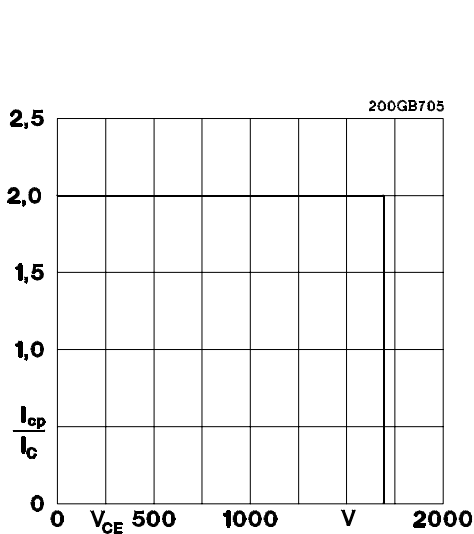


Fig. 5 Turn-off safe operating area (RBSOA)

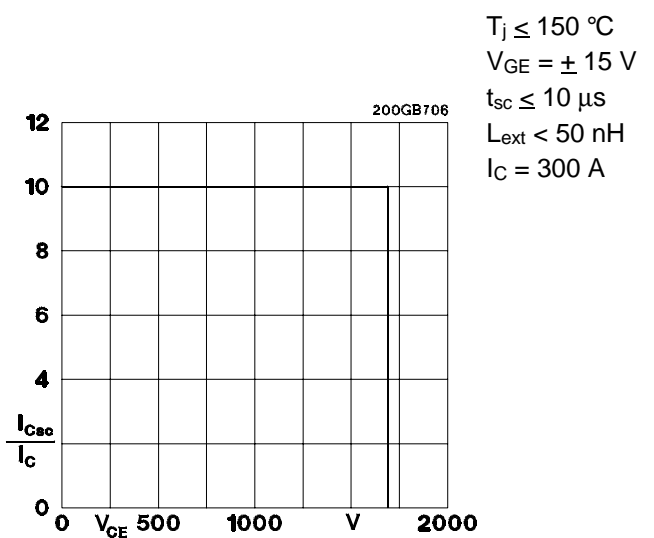


Fig. 6 Safe operating area at short circuit  $I_C = f(V_{CE})$

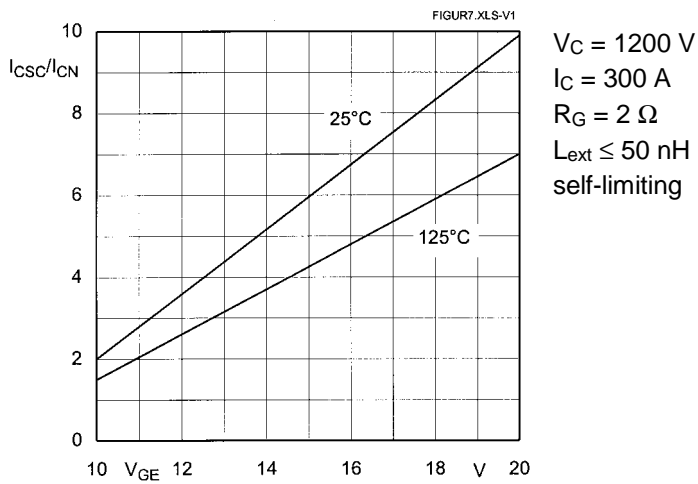


Fig. 7 Short circuit current vs. turn-on gate voltage

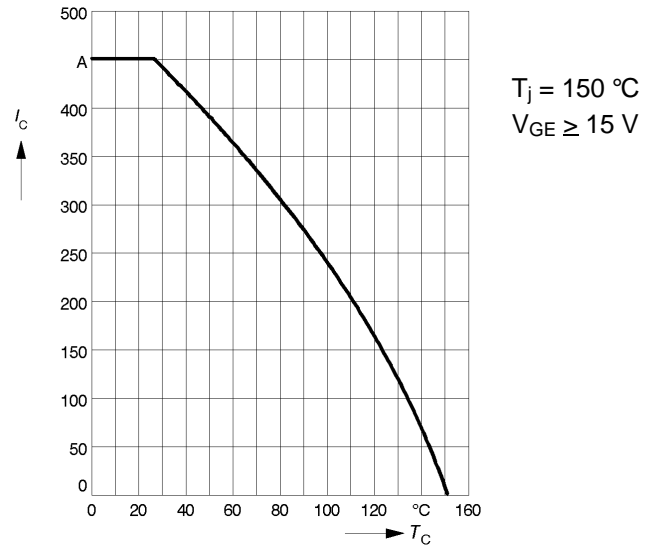


Fig. 8 Rated current vs. temperature  $I_C = f(T_C)$

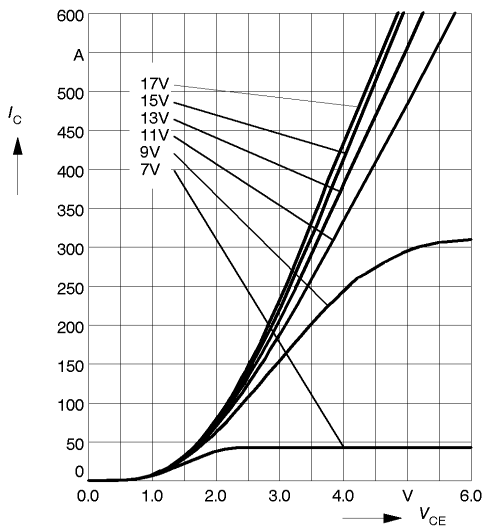


Fig. 9 Typ. output characteristic,  $t_p = 80 \mu\text{s}$ ;  $T_j = 25 \text{ }^\circ\text{C}$

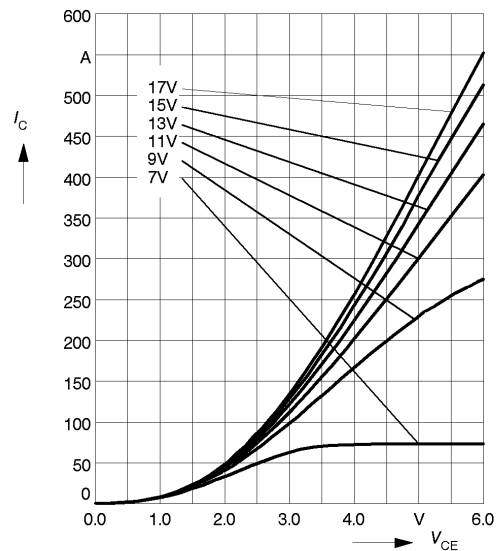


Fig. 10 Typ. output characteristic,  $t_p = 80 \mu\text{s}$ ;  $T_j = 125 \text{ }^\circ\text{C}$

$$P_{\text{cond}(t)} = V_{CE\text{sat}(t)} \cdot I_C(t)$$

$$V_{CE\text{sat}(t)} = V_{CE(TO)(T_j)} + r_{CE(T_j)} \cdot I_C(t)$$

$$V_{CE(TO)(T_j)} \leq 1,9 + 0,003 (T_j - 25) \text{ [V]}$$

$$r_{CE(T_j)} = 0,006 + 0,00002 (T_j - 25) \text{ [\Omega]}$$

$$\text{valid for } V_{GE} = +15 \frac{+2}{-1} \text{ [V]; } I_C \geq 0,3 I_{C\text{nom}}$$

Fig. 11 Typ. saturation characteristic (IGBT)  
 Calculation elements and equations

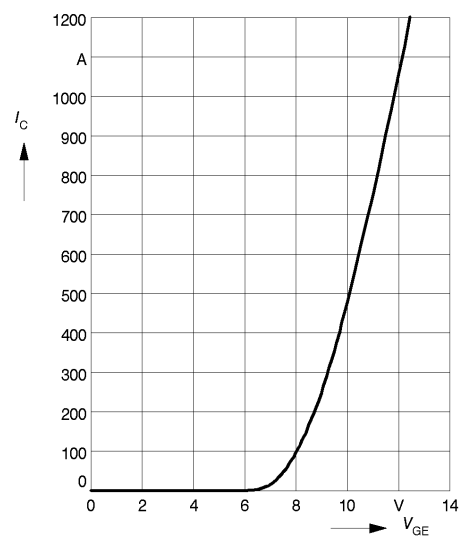


Fig. 12 Typ. transfer characteristic,  $t_p = 80 \mu\text{s}$ ;  $V_{CE} = 20 \text{ V}$

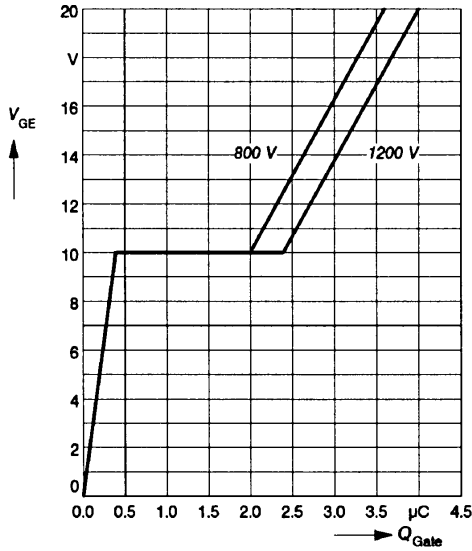


Fig. 13 Typ. gate charge characteristic

$I_{Cpuls} = 300 \text{ A}$

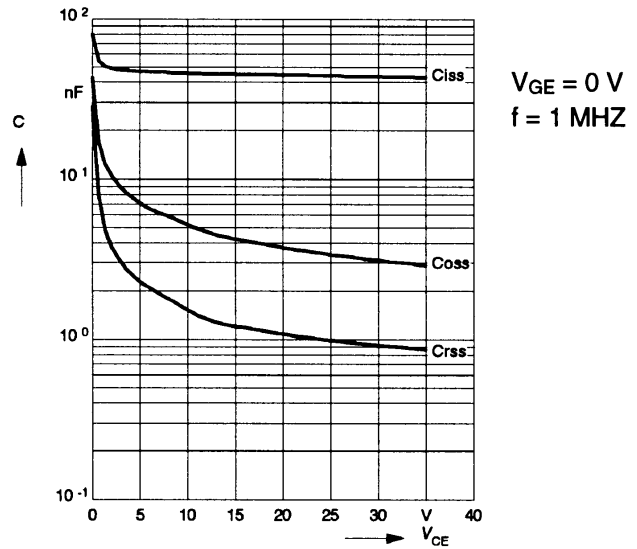


Fig. 14 Typ. capacitances vs.  $V_{CE}$

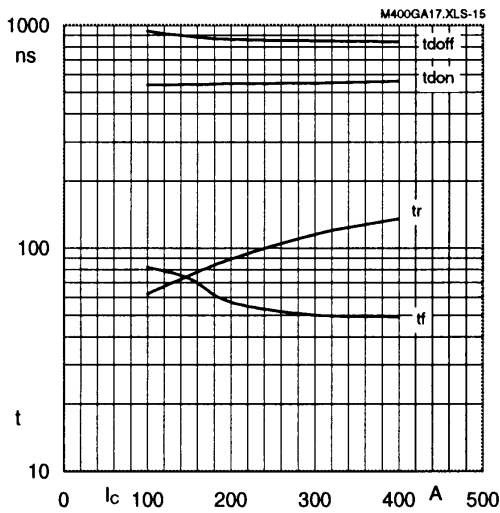


Fig. 15 Typ. switching times vs.  $I_C$

$T_j = 125 \text{ }^\circ\text{C}$   
 $V_{CC} = 1200 \text{ V}$   
 $V_{GE} = \pm 15 \text{ V}$   
 $R_g = 2 \text{ } \Omega$

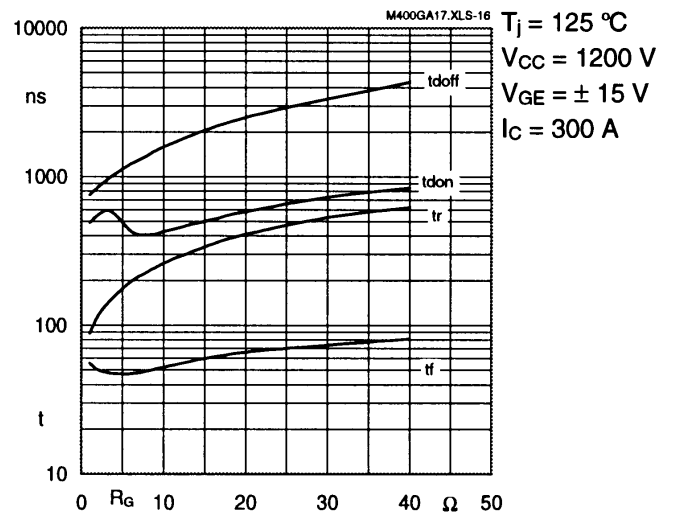


Fig. 16 Typ. switching times vs.  $R_G$

$T_j = 125 \text{ }^\circ\text{C}$   
 $V_{CC} = 1200 \text{ V}$   
 $V_{GE} = \pm 15 \text{ V}$   
 $I_C = 300 \text{ A}$

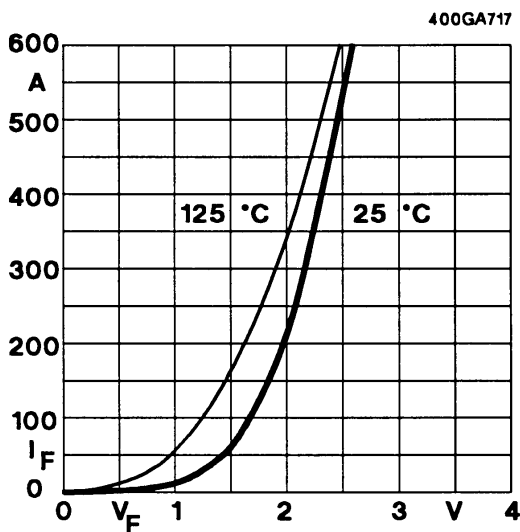


Fig. 17 Typ. CAL diode forward characteristic

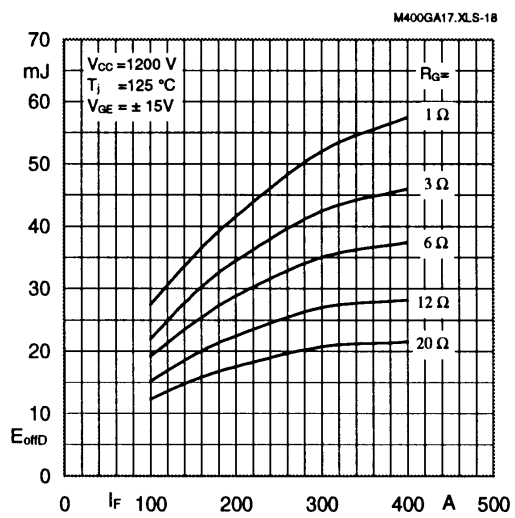


Fig. 18 Typ. Diode turn-off energy dissipation per pulse

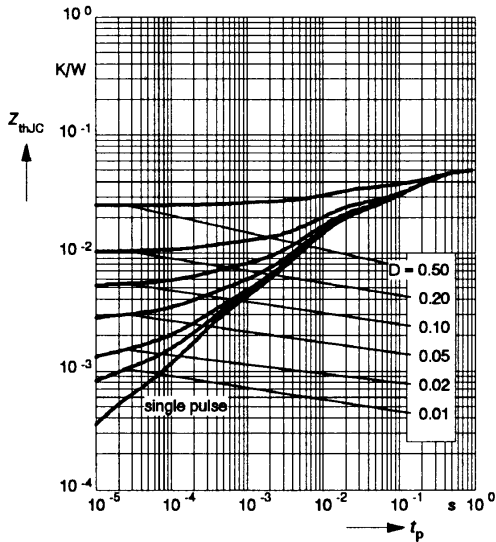


Fig. 19 Transient thermal impedance of IGBT:  $Z_{thjC} = f(t_p)$ ;  $D = t_p / t_c = t_p \cdot f$

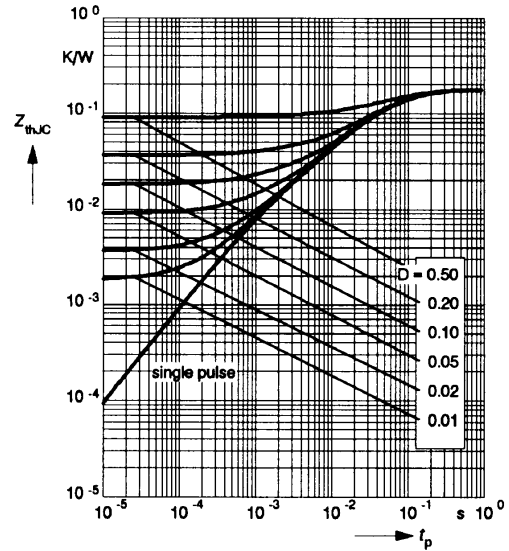


Fig. 20 Transient thermal impedance of inverse diode:  $Z_{thjCD} = f(t_p)$

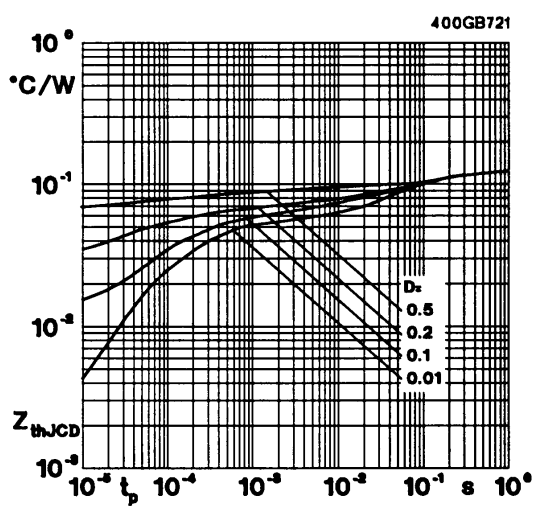


Fig. 21 Transient thermal impedance of Diode D1:  $Z_{thjCD} = f(t_p)$

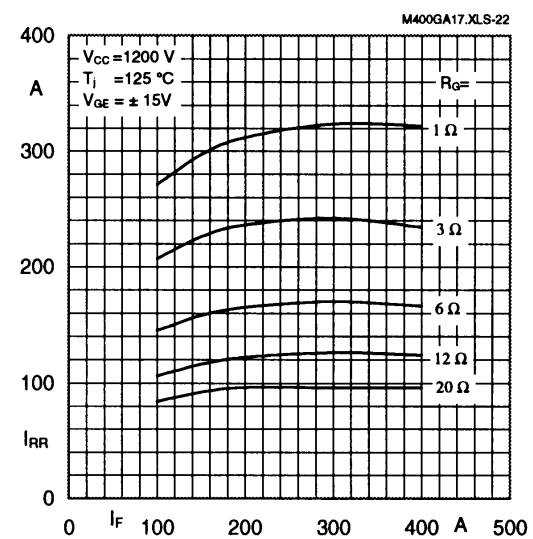


Fig. 22 Typ. CAL diode peak reverse recovery current  $I_{RR} = f(I_F; R_G)$

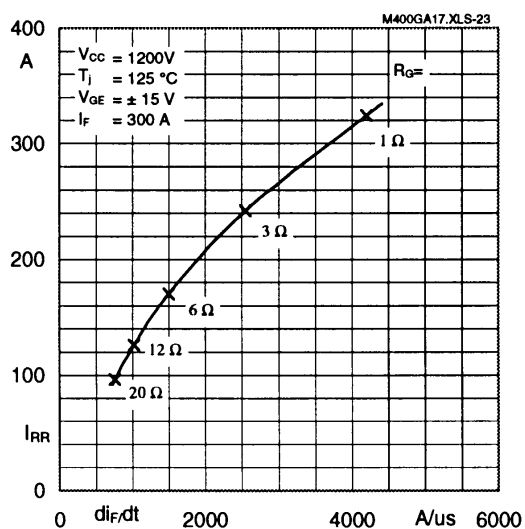


Fig. 23 Typ. CAL diode peak reverse recovery current  $I_{RR} = f(di_F/dt)$

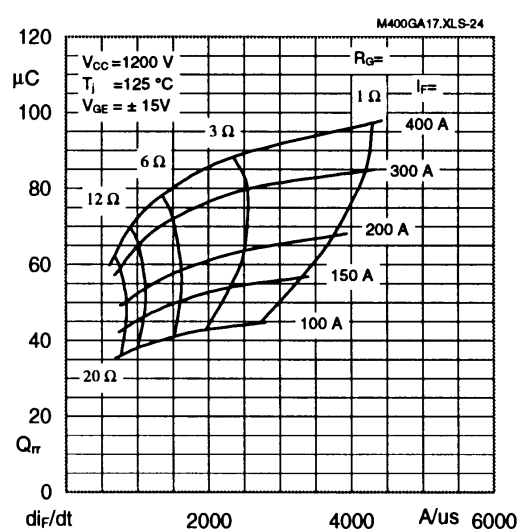


Fig. 24 Typ. CAL diode recovered charge  $Q_{rr}$

**SEMITRANS 4**

Case D 59

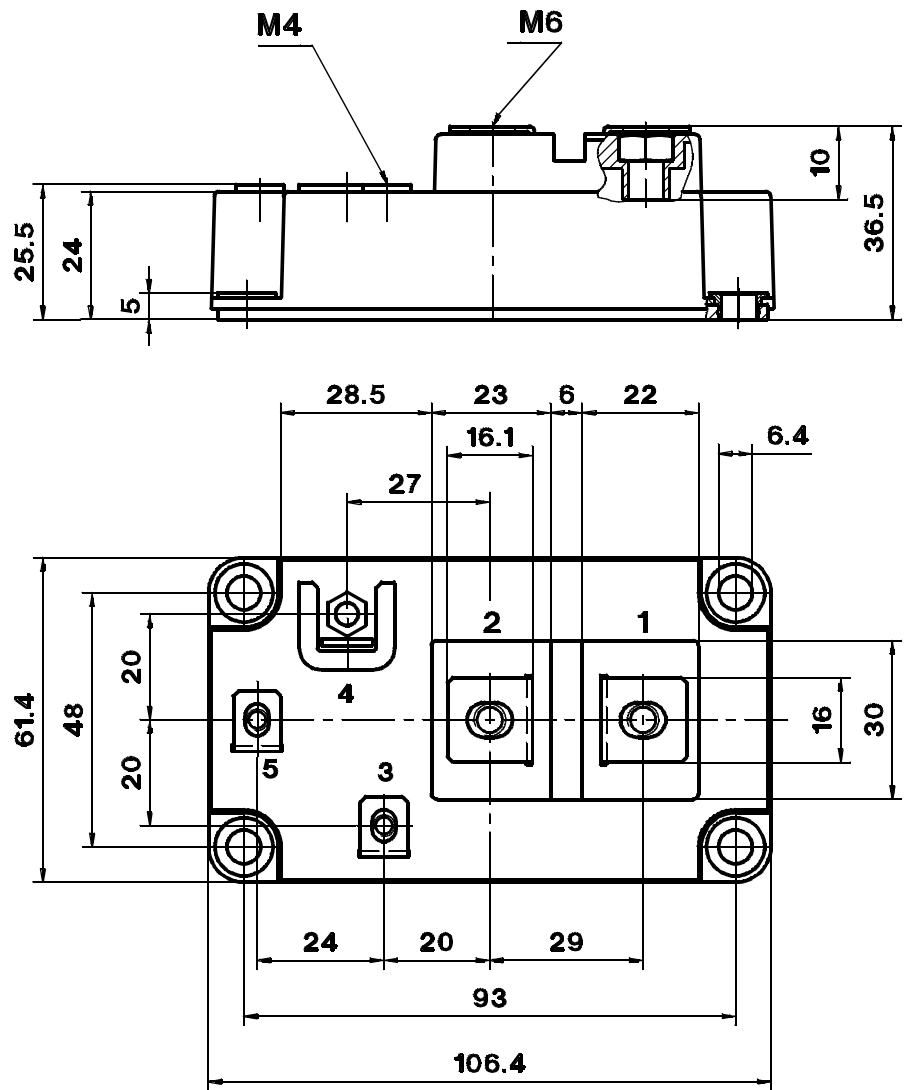
UL Recognized

File no. E 63 532

CASED59

SKM 400 GA 173 D

SKM 500 GA 123 D



Dimensions in mm

Option SKM 400 GA 173 D1S on request:  
Terminal 4 = collector sense  $V_{CE}$ , add suffix "S". → B 6 – 212.

Outline and circuit

Mechanical Data		Values			Units
Symbol	Conditions	min.	typ.	max.	
M <sub>1</sub>	to heatsink, SI Units to heatsink, US Units	(M6) 3	–	5	Nm lb.in.
M <sub>2</sub>	for terminals, SI Units for terminals US Units	(M6/M4) 2,5/1,1 22/10	–	5/2 44/18	Nm lb.in.
a		–	–	5x9,81	m/s <sup>2</sup>
w		–	–	330	g

**This is an electrostatic discharge sensitive device (ESDS). Please observe the international standard IEC 747-1, Chapter IX.**

Three devices are supplied in one SEMIBOX B without mounting hardware, which can be ordered separately under Ident No. 33321100 (for 10 SEMITRANS 4). Larger packing units of 12 and 20 pieces are used if suitable  
Accessories → B 6 - 4.  
SEMIBOX B → C - 2.